

**Search Notes**

Application/Control No.

10/537,329

Examiner

LOIS ZHENG

Applicant(s)/Patent under  
Reexamination

NAKAYAMA ET AL.

Art Unit

1793

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship search	2/26/2008	LLZ
EAST search	2/28/2008	LLZ